Avtomatika i Telemekhanika 1995 N12, pages 138-143

A binary-counter-based test generator in compact testing systems

Stolov E.
Kazan Federal University, 420008, Kremlevskaya 18, Kazan, Russia

Abstract

The use of the modified binary counter, as a test generator, is shown to allow to detect 100% of errors of the certain type in the combination scheme in the corresponding choice of the signature analyzer. If, as a result of reswitching, it is possible to apply signals from S counter minor digits to arbitrary S inputs of the programmable logic matrix then all the errors of multiplicity S and less in the column of the unit AND of the programmable logic matrix will be detected as a result of testing.